

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceed the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-35835
 - Class Q Military
 - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
- Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

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- High-Current 3-State Inverting Outputs Can Drive up to 15 LSTTL Loads
- Package Options Include Plastic Small-Outline (DW) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

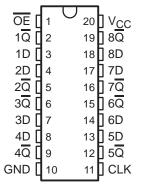
description

These 8-bit flip-flops feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

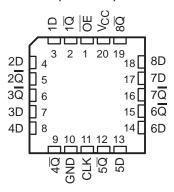
The eight flip-flops of the 'HC534 are edge-triggered D-type flip-flops. On the positive transition of the clock (CLK) input, the \overline{Q} outputs are set to the complement of the logic states that were set up at the data (D) inputs. The 'HC534 are functionally equivalent to the 'HC374, but the 'HC534 have inverted outputs.

An output-enable (OE) input places the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

SN54HC534 . . . J OR W PACKAGE SN74HC534 . . . DW OR N PACKAGE (TOP VIEW)



SN54HC534 . . . FK PACKAGE (TOP VIEW)



OE does not affect the internal operations of the flip-flops. Old data can be retained or new data can be entered while the outputs are off.

The SN54HC534 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HC534 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE (each flip-flop)

	INPUTS	OUTPUT	
OE	CLK	D	Q
L	↑	Н	L
L	\uparrow	L	Н
L	H or L	Χ	\overline{Q}_0
Н	Χ	Χ	Z

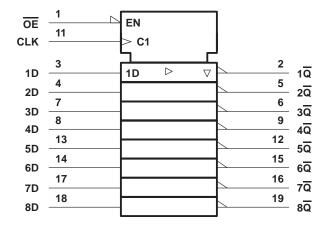


Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



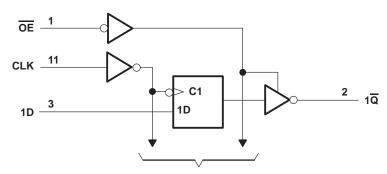
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logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



To Seven Other Channels

absolute maximum ratings over operating free-air temperature range[‡]

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input clamp current, $I_{ K }(V_1 < 0 \text{ or } V_1 > V_{CC})$ (see Note 1)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±35 mA
Continuous current through V _{CC} or GND	±70 mA
Package thermal impedance, θ _{JA} (see Note 2): DW package	97°C/W
N package	67°C/W
Storage temperature range, T _{stq}	–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.



recommended operating conditions

			SN	SN54HC534			SN74HC534			
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
Vcc	Supply voltage		2	5	6	2	5	6	V	
		V _{CC} = 2 V	1.5			1.5				
ViH	High-level input voltage	V _{CC} = 4.5 V	3.15			3.15			V	
		V _{CC} = 6 V	4.2			4.2				
	Low-level input voltage	V _{CC} = 2 V	0		0.5	0		0.5		
VIL		V _{CC} = 4.5 V	0		1.35	0		1.35	⊣ I	
		VCC = 6 V	0		1.8	0		1.8		
٧ı	Input voltage		0		VCC	0		VCC	V	
Vo	Output voltage		0		VCC	0		VCC	V	
		V _{CC} = 2 V	0		1000	0		1000		
t _t	Input transition (rise and fall) time	V _{CC} = 4.5 V	0		500	0		500	ns	
		V _{CC} = 6 V	0		400	0		400		
TA	Operating free-air temperature		-55		125	-40		85	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS		V	T _A = 25°C			SN54HC534		SN74HC534		LINUT
PARAMETER			Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		1.9		
		I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
Voн	VI = VIH or VIL		6 V	5.9	5.999		5.9		5.9		V
		I _{OH} = -6 mA	4.5 V	3.98	4.3		3.7		3.84		
		$I_{OH} = -7.8 \text{ mA}$	6 V	5.48	5.8		5.2		5.34		
	VI = VIH or VIL	I _{OL} = 20 μA	2 V		0.002	0.1		0.1		0.1	
			4.5 V		0.001	0.1		0.1		0.1	
VOL			6 V		0.001	0.1		0.1		0.1	V
		I _{OL} = 6 mA	4.5 V		0.17	0.26		0.4		0.33	
		$I_{OL} = 7.8 \text{ mA}$	6 V		0.15	0.26		0.4		0.33	
lį	$V_I = V_{CC}$ or 0		6 V		±0.1	±100		±1000		±1000	nA
loz	$V_O = V_{CC}$ or 0,	$V_I = V_{IH}$ or V_{IL}	6 V		±0.01	±0.5		±10		±5	μΑ
Icc	$V_I = V_{CC}$ or 0,	I _O = 0	6 V			8		160		80	μΑ
Ci		_	2 V to 6 V		3	10		10		10	рF

SN54HC534, SN74HC534 OCTAL EDGE-TRIGGERED D-TYPE FLIP-FLOPS WITH 3-STATE OUTPUTS

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timing requirements over recommended operating free-air temperature range (unless otherwise noted)

		Vaa	T _A = :	25°C	SN54HC534		SN74HC534		UNIT
		v _{cc}	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
		2 V	0	6	0	4.2	0	5	
fclock	Clock frequency	4.5 V	0	31	0	21	0	25	MHz
		6 V	0	36	0	25	0	29	
	Pulse duration, CLK high or low	2 V	80		120		100		
t _W		4.5 V	16		24		20		ns
		6 V	14		20		17		
		2 V	100		150		125		ns
t _{su}	Setup time, data before CLK↑	4.5 V	20		30		25		
		6 V	17		26		21		
	Hold time, data after CLK↑	2 V	5		5		5		ns
th		4.5 V	5		5		5		
		6 V	5		5		5		

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

DADAMETED	FROM	то	V	T _A = 25°C			SN54HC534		SN74HC534		LINIT		
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT		
			2 V	6	11		4.2		5				
f _{max}			4.5 V	31	36		21		25		MHz		
			6 V	36	40		25		29				
			2 V		88	180		270		225			
^t pd	CLK	Any Q	4.5 V		28	36		54		45	ns		
			6 V		24	31		46		38			
		Any Q	2 V		77	150		225		190			
t _{en}	ŌĒ		Any Q	Any \overline{Q}	4.5 V		26	30		45		38	ns
			6 V		23	26		38		32			
			2 V		51	150		225		190			
t _{dis}	ŌĒ	Any Q	4.5 V		25	30		45		38	ns		
			6 V		23	26		38		32			
			2 V		28	60		90		75			
t _t		Any Q	4.5 V		8	12		18		15	ns		
			6 V		6	10		15		13			

SN54HC534, SN74HC534 OCTAL EDGE-TRIGGERED D-TYPE FLIP-FLOPS WITH 3-STATE OUTPUTS

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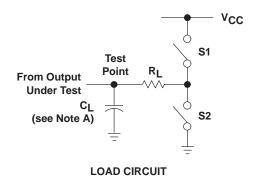
switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 1)

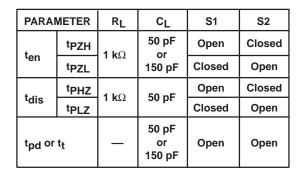
PARAMETER	FROM	TO (OUTPUT)	Vaa	T,	ղ = 25°C	;	SN54H	C534	SN74H	C534	UNIT
PARAMETER	(INPUT)		VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V		105	230		345		290	
t _{pd}	CLK	Any Q	4.5 V		35	46		69		58	ns
			6 V		31	39		58		49	
	ŌĒ	Any Q	2 V		95	200		300		250	
t _{en}			4.5 V		32	40		60		50	ns
			6 V		29	34		51		43	
		Any $\overline{\mathbb{Q}}$	2 V		60	210		315		265	
t _t			4.5 V		17	42		63		53	ns
				6 V		14	36		53		45

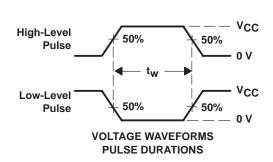
operating characteristics, $T_A = 25^{\circ}C$

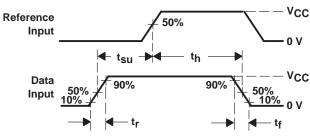
	PARAMETER	TEST CONDITIONS	TYP	UNIT
Cp	Power dissipation capacitance per flip-flop	No load	100	pF

PARAMETER MEASUREMENT INFORMATION

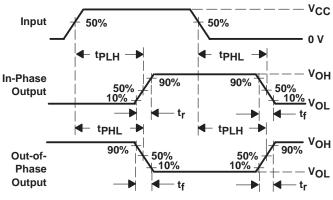


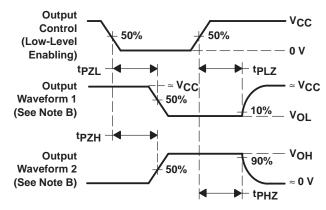






VOLTAGE WAVEFORMS
SETUP AND HOLD AND INPUT RISE AND FALL TIMES





VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT TRANSITION TIMES

VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f = 6 ns, t_f = 6 ns.
- D. For clock inputs, f_{max} is measured when the input duty cycle is 50%.
- E. The outputs are measured one at a time with one input transition per measurement.
- F. tpLZ and tpHZ are the same as tdis.
- G. tpZL and tpZH are the same as ten.
- H. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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